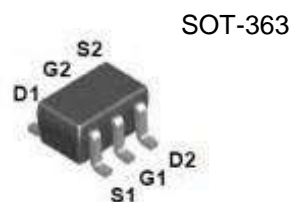


## Dual N-Channel High Density Trench MOSFET

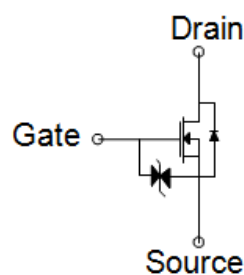
### Features:

- Super high dense cell trench design for low  $R_{DS(on)}$ .
- Rugged and reliable.
- Surface Mount package.



### PRODUCT SUMMARY

$V_{DSS}$	$I_D$	$R_{DS(on)}$ (m-ohm) Max
20V	0.6A	500 @ $V_{GS} = 4.5V$
	0.4A	800 @ $V_{GS} = 2.5V$



ESD PROTECTION DIODE

### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Drain Current-Continuous <sup>a</sup> @ $T_A = 25\text{ }^\circ\text{C}$ -Pulse <sup>b</sup>	$I_D$	0.8	A
	$I_{DM}$	3.2	A
Drain-Source Diode Forward Current <sup>a</sup>	$I_S$	0.6	A
Maximum Power Dissipation <sup>a</sup>	$P_D$	$T_A = 25\text{ }^\circ\text{C}$	0.5
		$T_A = 75\text{ }^\circ\text{C}$	0.3
Operating Junction and Storage Temperature Range	$T_J, T_{STG}$	- 55 to 150	$^\circ\text{C}$

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient <sup>a</sup>	$R_{thJA}$	250	$^\circ\text{C/W}$
--	------------	-----	--------------------

Note

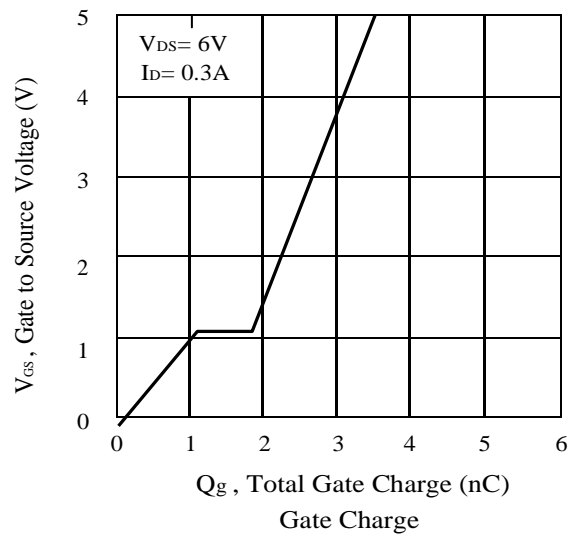
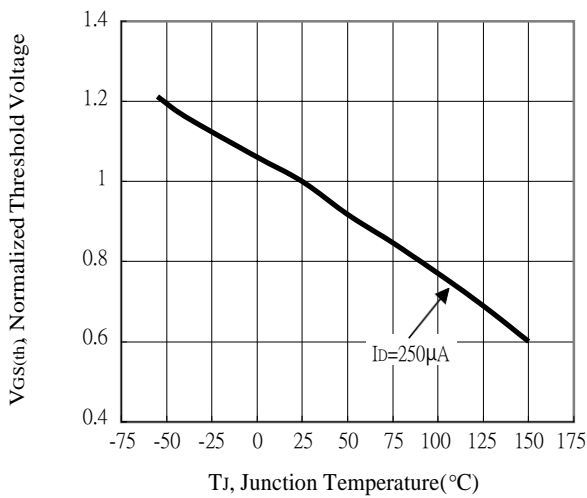
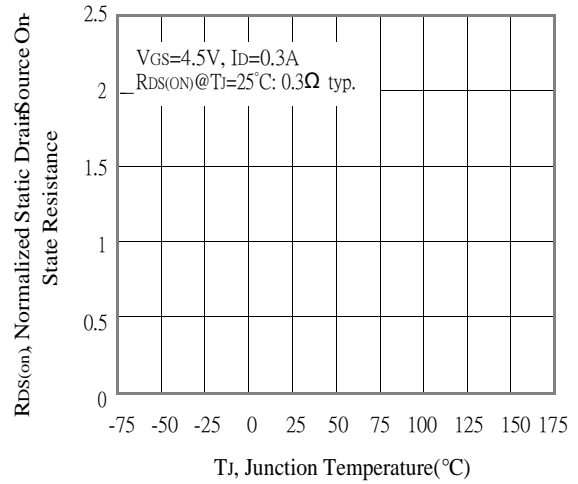
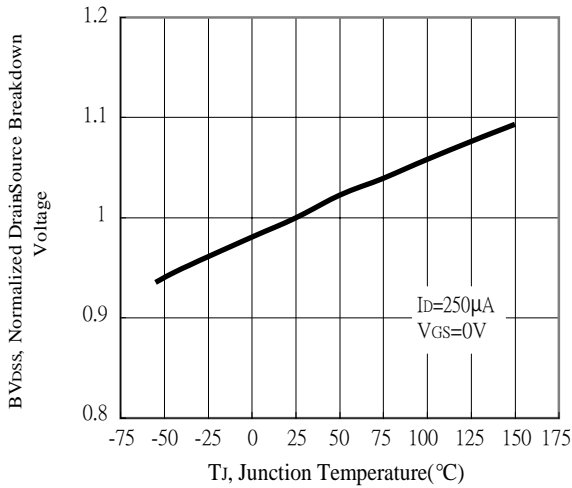
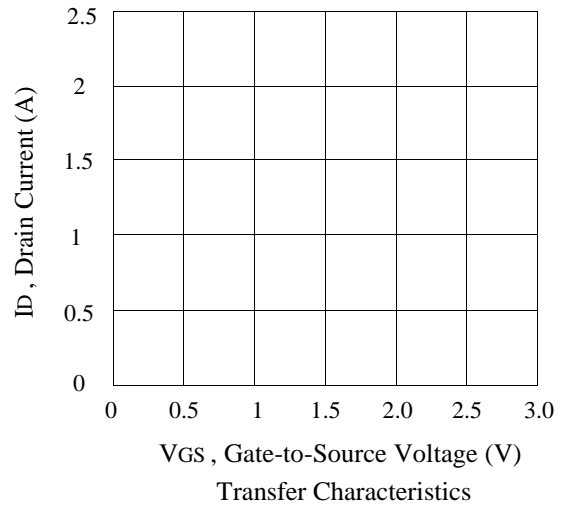
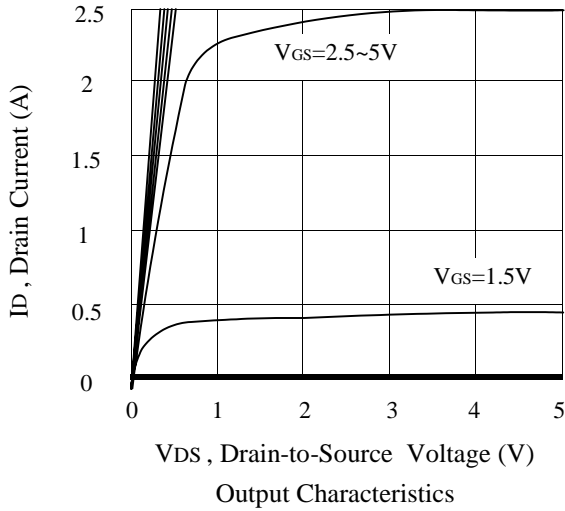
a. Surface Mounted on FR4 Board,  $t \leq 10\text{sec}$ .

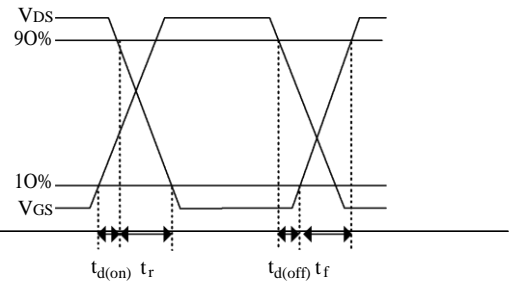
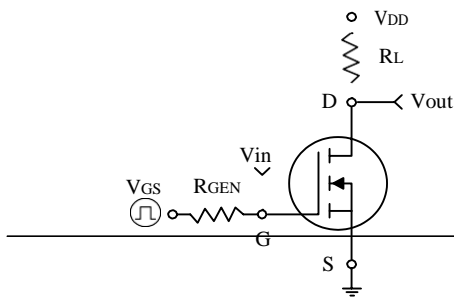
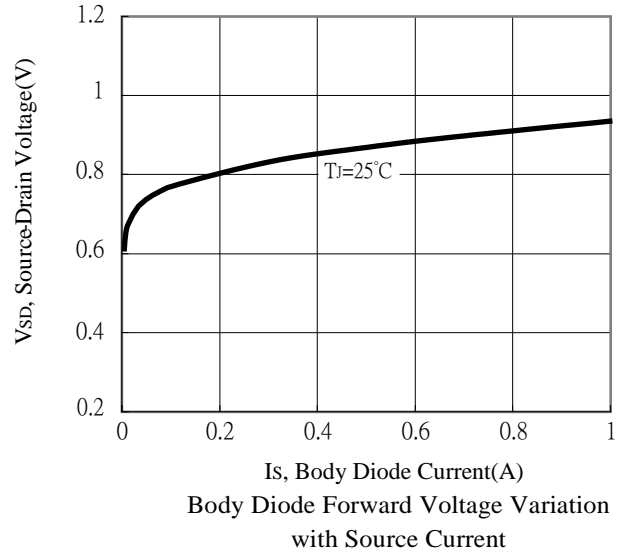
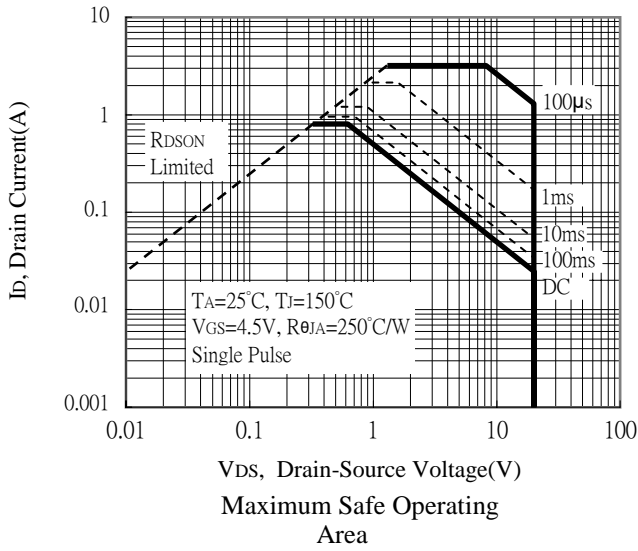
b. Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C unless otherwise noted)**

Parameter	Symbol	Condition	Min	Typ <sup>c</sup>	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0V , I <sub>D</sub> = 250uA	20			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 20V , V <sub>GS</sub> = 0V			1	uA
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ±8V , V <sub>DS</sub> = 0V			±10	uA
<b>ON CHARACTERISTICS<sup>b</sup></b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250uA	0.5	0.7	1	V
Drain-Source On-State Resistance	R <sub>DSON</sub>	V <sub>GS</sub> = 4.5V , I <sub>D</sub> = 0.6A		300	500	m-ohm
		V <sub>GS</sub> = 2.5V , I <sub>D</sub> = 0.4A		600	800	
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 5V , I <sub>D</sub> = 0.3A		3		S
<b>DRAIN-SOURCE DIODE CHARACTERISTICS<sup>b</sup></b>						
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0V , I <sub>S</sub> = 0.3A		0.7	1.2	V
<b>DYNAMIC CHARACTERISTICS<sup>c</sup></b>						
Input Capacitance	C <sub>ISS</sub>	V <sub>DS</sub> = 6V , V <sub>GS</sub> = 0V f = 1.0MHz		42		pF
Output Capacitance	C <sub>OSS</sub>			23		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			19		pF
<b>SWITCHING CHARACTERISTICS<sup>c</sup></b>						
Turn-On Delay Time	t <sub>D(ON)</sub>	V <sub>DD</sub> = 6V , I <sub>D</sub> = 0.3A		5	9	ns
Rise Time	t <sub>r</sub>		V <sub>GEN</sub> = 4.5V		15	42
Turn-Off Delay Time	t <sub>D(OFF)</sub>	R <sub>L</sub> = 6 ohm		25	28	ns
Fall Time	t <sub>f</sub>	R <sub>GEN</sub> = 6 ohm		7.6		ns
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 6V		3.4		nC
Gate-Source Charge	Q <sub>gs</sub>	I <sub>D</sub> = 0.3A		2.5		nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> = 4.5V		1.7		nC

Note  
b. Pulse Test Pulse width ≤ 300us , Duty Cycle ≤ 2%.  
c. Guaranteed by design , not subject to production testing .





Switching Test Circuit and Switching Waveforms

